Nordic Nanolab User Meeting 2024

NorFab University of Oslo and SINTEF, Oslo, Norway 3 – 4 June 2024

Preliminary Program Monday 3 June



19:30 Conference dinner at Samfunnssalen in the center of Oslo





Preliminary Program Tuesday 4 June					
	09:00	Characterisation	Thin Film technologies	mpetitive Advantage by Em. Etching technologies Ion Beam Etching (basic) Mats Hagberg, Chalmers	bracing MEMS Technology Lithography High-Resolution Hexagonal Patterns Fabricated by Dipole Cross Exposure in Deep UV-Lithography and their Applications (advanced) Matthias Kiel /Meena Dhankar
	10:30 Coffee				
	11:00	Characterisation Demo: Analyzing EBSD/TKD data with hyperspy, kikuchipy (basic/advanced) Håkon Ånes, NTNU	on silicon for single photon detectors by different deposition methods: Molecular Beam Epitaxy versus Sputtering. (Intermediate) Adrian Iovan, KTH	Etching technologies Advanced Plasma Etch (Advanced) James Dekker, VTT	Lithography Work on Automated metrology to improve process development and EBL performance, Niclas Lindvall/Marcus Rommel, Chalmers E-Beam&UV Mix-and- Match Thomas Pedersen /Elena Lopez, DTU Nanolab
	Maria Asplund, Chalmers: <i>Bioelectronic microsystems engineering: for patients, for cyborgs and fa</i> 11:55 <i>neuroscientists at work</i> 12:30 Lunch				
	13:15	Characterisation	Thin Film technologies Pulsed Laser Deposition: From High Temperature Superconductors to Atomically Engineered Interfaces. (Advanced) Alexei Kalaboukhov, Chalmers	Etching technologies	Lithography Maskless lithography - parameter control, Grigory Skoblin, Chalmers (include results from Andreas Liapis Aalto)
	14:00 14:15	Coffee Peter Böggild, DTU: Thermal scanning probe lithography tool with in-situ imaging and grayscale			
	14:50	Wrap up			
	15:15	Bus to Gardermoen			



